

Docket No.: 216648US-2

"RESPONSE UNDER 37 CFR 1.116-EXPEDITED PROCEDURE EXAMINING GROUP\_ 2822"

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FEB 2 0 2004

RE: Application Serial No.: 10/001,977

Hiroyoshi TANIMOTO, et al. Applicants:

Filing Date: December 5, 2001

For: SEMICONDUCTOR DEVICE, METHOD OF

MANUFACTURING SEMICONDUCTOR DEVICE, AND SYSTEM FOR EVALUATING ELECTRICAL CHARACTERISTICS OF SEMICONDUCTOR

DEVICE

COMMISSIONER FOR PATENTS

ALEXANDRIA, VIRGINIA 22313

Group Art Unit: 2822 Examiner: PERKINS, P. E.

SIR:

Attached hereto for filing are the following papers:

REQUEST FOR RECONSIDERATION UNDER 37 C.F.R. § 1.116

Our check in the amount of \$0.00 is attached covering any required fees. In the event any variance exists between the amount enclosed and the Patent Office charges for filing the above-noted documents, including any fees required under 37 C.F.R 1.136 for any necessary Extension of Time to make the filing of the attached documents timely, please charge or credit the difference to our Deposit Account No. 15-0030. Further, if these papers are not considered timely filed, then a petition is hereby made under 37 C.F.R. 1.136 for the necessary extension of time. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND, MAIER & NEUSTADT, P.C.

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## IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF

HIROYOSHI TANIMOTO, ET AL.

: EXAMINER: PERKINS, P. E.

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SEMICONDUCTOR DEVICE

## REQUEST FOR RECONSIDERATION UNDER 37 C.F.R. § 1.116

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

SIR:

In response to the Office Action dated November 18, 2003, Applicants request reconsideration of the above-identified application.

Remarks begin on page 2 of this paper.